

*Online supporting information for:*

# Stability and Core-level Signature of Nitrogen Dopants in Carbonaceous Materials

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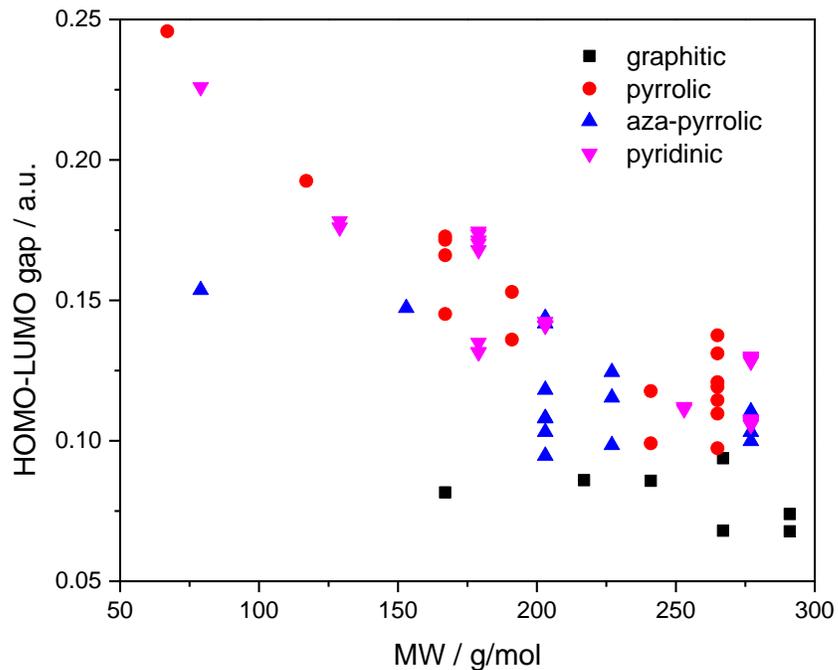
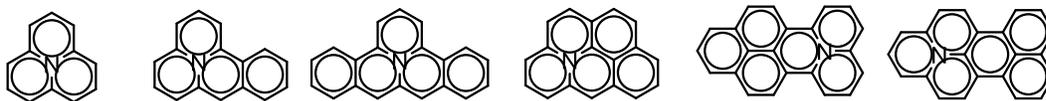


Figure S1. HOMO-LUMO gap versus molecular weight for the 69 model compounds.

graphitic



quaternary valley

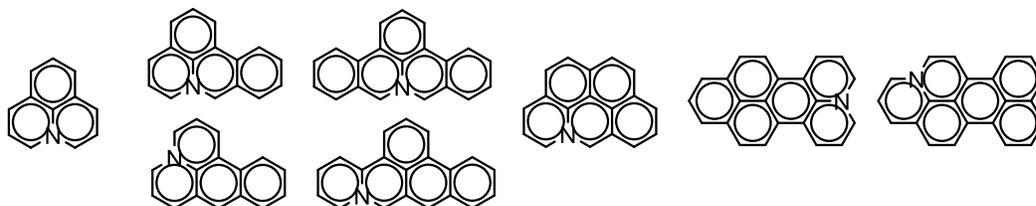


Figure S2. Model compounds containing graphitic and quaternary-valley nitrogen atoms.

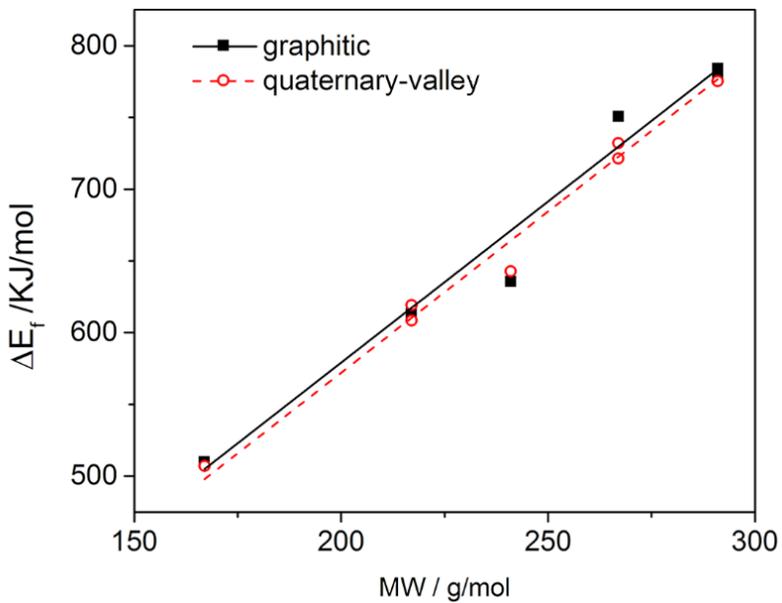


Figure S3. Calculated formation energies of compounds containing graphitic and quaternary-valley nitrogen dopants.

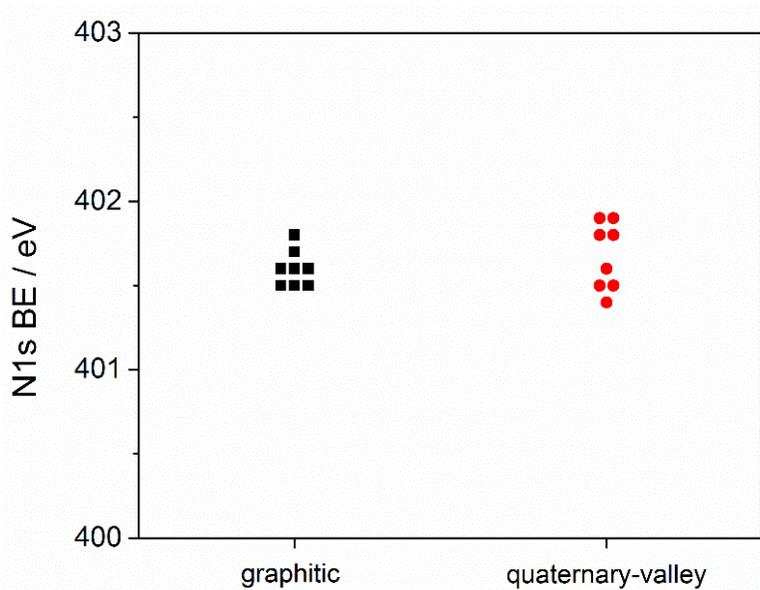


Figure S4. Comparison of simulated N 1s binding energies of graphitic and quaternary-valley nitrogen atoms.

**How we chose the small N-containing molecules for their experimental N 1s binding energies:** In the National Institute of Standards and Technology (NIST) X-ray Photoelectron Spectroscopy Database online,<sup>1</sup> there are hundreds of nitrogen-containing compounds whose experimental XPS spectra and N 1s binding energies are available. Most of the compounds are organometallic. For this study, we picked from the database those N-containing organic compounds (shown in Figure 4 of the main text) similar to our model compounds (Figure 1 of the main text), such as pyrrole, pyridine, porphyrin, amine, azobenzene and nitrobenzene molecules. Their experimental N 1s binding energies range from 397.9 to 405.9 eV.<sup>1</sup>

Reference:

1. Naumkin, A. V.; Kraut-Vass, A.; Gaarenstroom, S. W. and Powell, C. J. NIST X-ray Photoelectron Spectroscopy Database, <http://srdata.nist.gov/xps/>; last accessed, June 9, 2015.